FOX 15™
FULL WAFER CONTACT

Full-Wafer Burn-In & Test System

300 mm Single Touchdown Burn-in and Test

System Benefits:

- Cost-effective Solution for Producing:
    - Known-Good-Die (KGD) for MultiChip Packages
    - Zero-defect automotive ICs
- Production Proven Full-Wafer Burn-In Solution:
    - Protects wafers and probe cards with individual power channel over-current protection
    - High volume production capacity — 15 wafers per load
- Reduces Costs:
    - Reduces burn-in times by enabling higher burn-in temperatures
    - Reduces final test costs by functionally testing wafer during burn-in
    - Saves packaging costs by deferring until after burn-in
    - Highly reliable — 4th generation design

“Changing the Way ICs Are Tested”

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CERTIFIED QUALITY MANAGEMENT SYSTEM ISO 9001:2008
DNV

AEHR TEST SYSTEMS